

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.: ST 9903a

SERIAL NO. 09/890,656

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT: Reinhard Schauer et al.

FILING DATE: August 2, 2001

GROUP: 2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TT	AA	5,935,320	8/10/99	Graef et al.	—	—	
	AB						
	AC						
	AD						
	AE						
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	AH						
	AI						
	AJ						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
TT	AL	0725 169	8/7/96	Europe	—	—		
TT	AM	19823962	12/2/99	Germany	—	—		
TT	AN	0959 154	11/24/99	Europe	—	—		
TT	AO	0644 588	3/22/95	Europe	—	—		
TT	AP	0829 559	12/15/99	Europe	—	—		

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

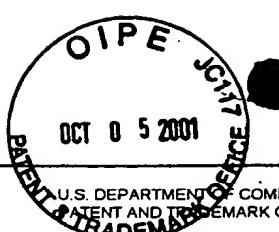
TT	AR	Electrochemical Society Proceedings, Vol. 98-1, pp. 855 - 861
		Jpn. J. Appl. Phys., Vol. 36, 1997, pp. 2565 - 2570
T1	AT	English Document Abstract AN 1996-356122 corresponding to EP 0 725 169

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DATE CONSIDERED

01-08-03



FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. : ST 99023a	SERIAL NO. 09/890,656		
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							YES NO
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TT	AR	English Derwent Abstract AN 2000- 024759 corresponding to DE 19823962					
TT		AS	Lee, S.K. et al., Appl. Phys. Lett.; 1989, vol. 54 (18) pp. 1775-1777				
TT	AT	Skelly, G and Adams, A.C.; J. Electrochemical Soc., 1973, vol. 120, pp. 116-122					
EXAMINER		Initials		DATE CONSIDERED		01-08-03	
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

FORM PTO-1449
(REV. 7-80)

ATTY. DOCKET NO.: ST9903a

SERIAL NO. 09/890,656

APPLICANT: Reinhard Schauer et al.

FILING DATE: August 2, 2001

GROUP: 2811

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	AR	SZE, S.M.: Physics of Semiconductor Devices, New York, Wiley, 1969, p. 43					
	AS	Ohshita, Y. et al; Journal of Crystal Growth, 1991, vol. 108, pp. 499-507					
	AT	Hammond, M.L.: Silicon Epitaxy, Solid State Technology, 1978, H.11, pp. 68-75					

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01-08-03



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		1983/84, vol. 41, no. 2, pp. 60-69
	AS	
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